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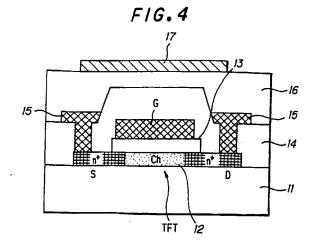
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(54) Method of processing a thin film on a substrate for display

(57)In a method of manufacturing semiconductor chips for display, a semiconductor thin film is first formed on an insulating substrate, and then a series of processes containing a heat-treatment process for the semiconductor thin film are carried out to form integrated thin film transistors on a sectioned area for one chip. Thereafter, pixel electrodes for one picture (frame) are formed within the sectioned area. During the series of processes, a laser pulse is irradiated onto the sectioned area by one shot to perform a heat treatment on the semiconductor thin film for one chip collectively and simultaneously (i.e., perform a batch heat treatment on the semiconductor thin film). Through the batch heat treatment, the crystallization of the semiconductor thin film is promoted. In addition, after the semiconductor thin film is doped with impurities, the activation of impurities doped in the semiconductor thin film can be performed by the batch heat treatment.



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EUROPEAN SEARCH REPORT

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Category	Citation of document with i	ndication, where appropriate,	Relevant	CLASSIFICATION OF THE
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	The present search report has	been drawn up for all claims		
	Place of search	Date of completion of the search		Examiner
	THE HAGUE	3 November 1997	Sch	uermans, N
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